

<b>Notice of References Cited</b>	Application/Control No. 11/853,501	Applicant(s)/Patent Under Reexamination HAMID ET AL.	
	Examiner SURESH MEMULA	Art Unit 2825	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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